

MSE-735

28.8.2023

29.8.2023

30.8.2023

DIA-003	
10:00	Introduction/Welcome
10:15	Introduction to STEM
	basics
	Signals, ADF/BF/HAADF
	Z-contrast, resolution
12:00	EO

DIA-003	
13:15	EELS basics
14:15	DA
	pause
14:30	Advanced STEM
	imaging, DPC
	VB
	pause
15:45	Advanced STEM
	4D-STEM
16:30	VB

DIA-003	
08:15	Phase contrast imaging
	HRTEM Simulations, NCSI
	practical: image simulations with JEMS
	building a model, importing a CIF
	simulating diffraction patterns SAED, HRTEM
10:00	pause
10:30	Field measurements in TEM
	Holography
	Lorentz-microscopy
11:30	VB

DIA-003	
13:15	Cs-TEM vs Cs-STEM
	VB
	practical: STEM image simulations
	with D. Probe
	VB
	pause
15:30	advanced EDX microanalysis
	artifacts, quantification
	MC
	Tomography
17:00	MC

Group 1	Group 2
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		THEMIS: MXC.012	
		Cs-TEM, Cs-STEM	
09:15	DEMO	EELS	
	Osiris: MXC.030		
	STEM, EDX		10:15
09:45			
10:30	THEMIS: MXC.012	DEMO	10:30
	Cs-TEM, Cs-STEM	Osiris: MXC.030	
	EELS	STEM, EDX	
			11:30
12:15			